



Advanced Coating Noise Direct Broadband Measurement

Eric Black, Akira Villar, Kenneth G. Libbrecht (*Caltech*)
Kate Dooley (*Vassar*), Chinyere Nwabugwu (*LSU*)

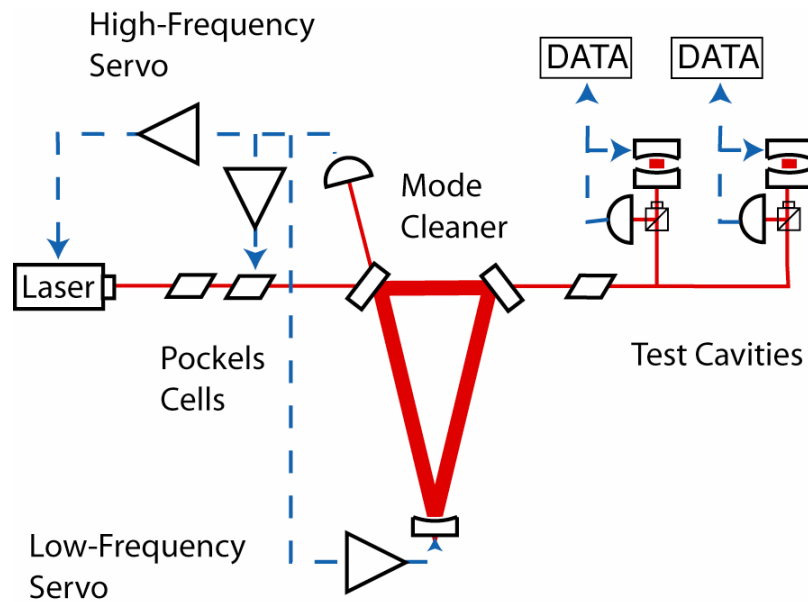
LSC Coating Meeting
August 13, 2005



Purpose

- Fluctuation-dissipation theorem predicts noise spectrum from Q .
- Q 's measured by ringdown for advanced coatings. Expect broadband noise to be reduced accordingly.
- As noise moves down, need to see if any unexpected noise sources are uncovered.
- Need to evaluate coatings for suitability in an actual, low-noise interferometer.

Thermal Noise Interferometer



- Fundamental-noise limited interferometer (thermal and shot).
- Measurement made as relevant to AdLIGO as possible in a small interferometer.
 - Lowest noise levels practical
 - Low-mechanical-loss substrates
 - Largest practical spot size



Resolving coating noise improvements

- Coating thermal noise must be improved by more than the resolution of the instrument ($\sim 10\%$), to draw any quantitative conclusions.
- Coating thermal noise must still be above the noise floor of the instrument.
 - Shot noise at high frequencies (laser power/visibility limited)
 - Substrate thermal noise at intermediate frequencies (spot-size limited)
 - Acoustic coupling to input optics (?) at low frequencies
- Coatings must be applied to TNI standard mirrors (4"x4").



Expected Improvement

- Loss angle for silica/undoped-tantala coatings = $2.7e-4$
- Loss angle for silica/doped-tantala coatings expected to be $1.7e-4$
- Expect $\sim 20\%$ reduction in noise floor, which should be clearly observable.

$$x_{\text{coating-thermal}}(f) \sim \sqrt{\frac{k_B T}{\omega Y f} \frac{d}{\omega} \phi_{\text{coating}}}$$

$$\frac{x_{\text{doped}}}{x_{\text{undoped}}} = \sqrt{\frac{1.7}{2.7}} = 0.79$$



Distinguishing Coating from Substrate Thermal Noise

Coating vs. substrate thermal noise...

$$x_{Th}^2(f) \sim \frac{k_B T}{\omega Y f} \left\{ \phi_{substrate} + \frac{d}{\omega} \phi_{coating} \right\}$$

Condition required to distinguish coating thermal noise from substrate thermal noise:

$$\phi_{coating} \gg \frac{\omega}{d} \phi_{substrate} \quad \text{For the TNI,} \quad \frac{\omega}{d} \approx \frac{160 \mu m}{5 \mu m} = 32$$

$$\phi_{substrate} \leq 3 \times 10^{-7}$$

Expect to resolve coatings from substrate as long as $\phi_{coating} \geq 1 \times 10^{-5}$

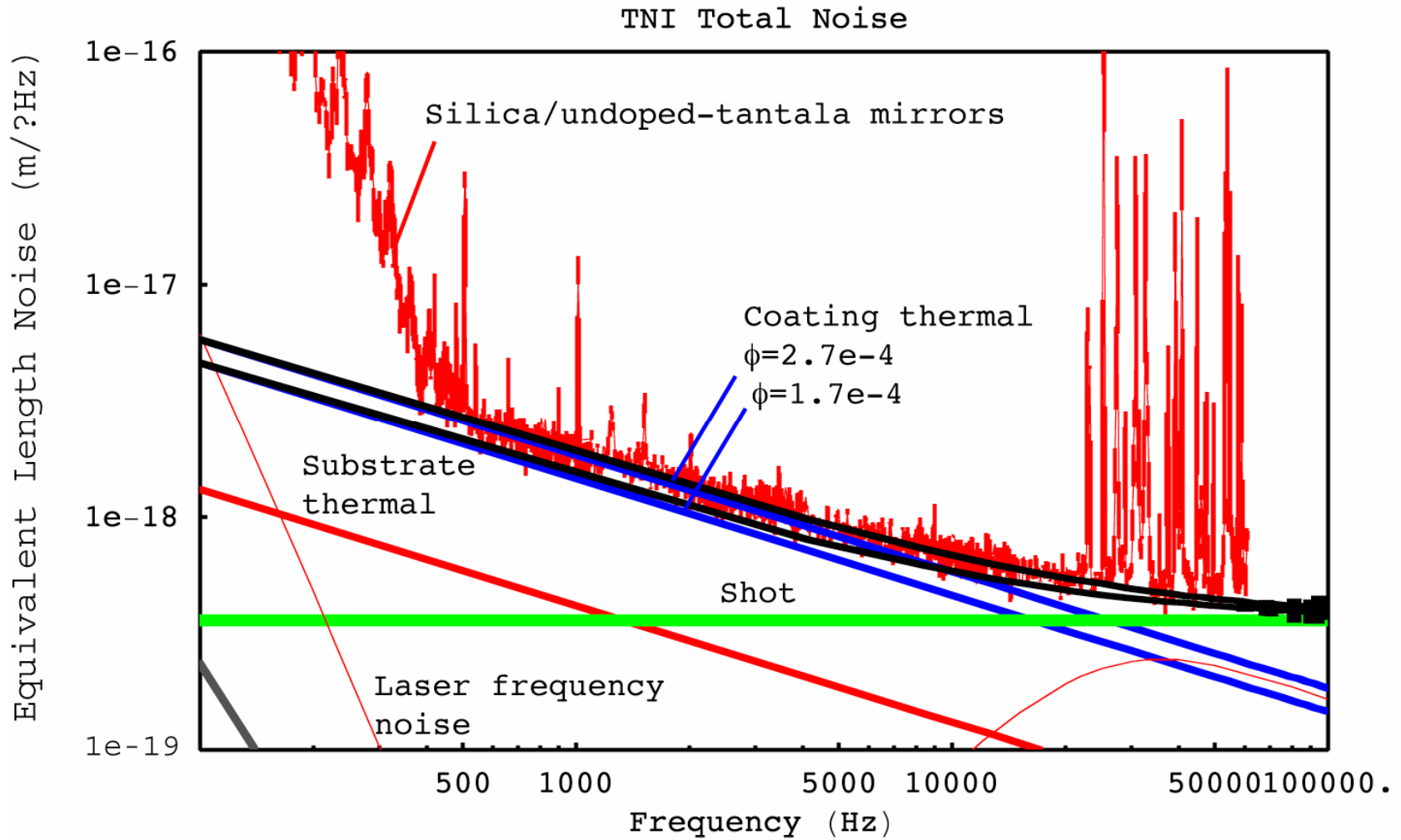


Instrument noise floor

- Shot noise should be $\sim 3e-19$ m/ $\sqrt{\text{Hz}}$
- Low frequency (acoustic?) noise falls off steeply above 500Hz
- Laser frequency noise, etc. negligible compared to thermal noise above 500Hz



Resolving coating noise improvements





Advanced Coating Measurement

- Most loss appears to be in tantala layers.
- Doping (Ti) reduces measured mechanical Q's.
- Advanced coatings were deposited on an existing set of 4"x4" fused-silica mirrors.
- Scheduled delivery of middle of May 2005, arrived June 30.
- Expect ~ six weeks from receipt of mirrors to data, based on sapphire experience.
- NAC mirrors installed, balanced, and aligned without incident.
- SAC visibility anomalously low (<50%).
- Sealed vacuum chamber August 9.
- First lock with new mirrors August 10.
- Preliminary noise floor not as low as expected.
- Debug upon return (August 16).